

## 40V N+N-Channel Enhancement Mode MOSFET

### Description

The AP30H04NF uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 40V$   $I_D = 30A$

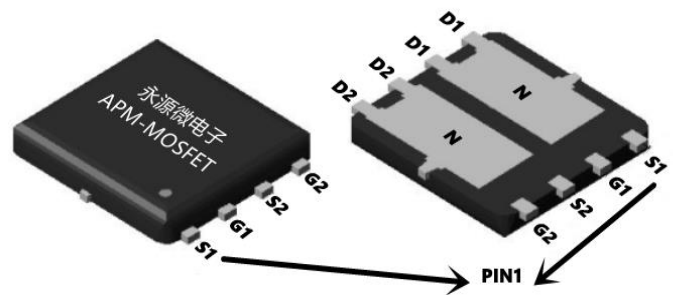
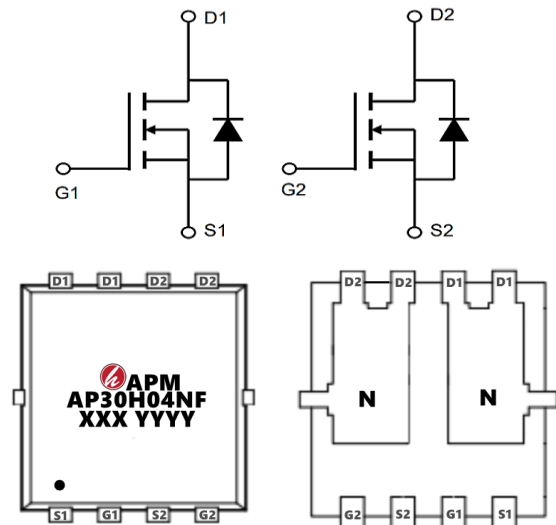
$R_{DS(ON)} < 14m\Omega$  @  $V_{GS}=10V$  (Type: **11mΩ**)

### Application

Wireless charging

Boost driver

Brushless motor



### Package Marking and Ordering Information

| Product ID | Pack       | Marking            | Qty(PCS) |
|------------|------------|--------------------|----------|
| AP30H04NF  | PDFN5*6-8L | AP30H04NF XXX YYYY | 5000     |

### Absolute Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise noted)

| Symbol                       | Parameter   | Rating     | Units              |
|------------------------------|---|------------|--------------------|
| $V_{DS}$                     | Drain-Source Voltage  | 40         | V                  |
| $V_{GS}$                     | Gate-Source Voltage   | $\pm 20$   | V                  |
| $I_D @ T_A=25^\circ\text{C}$ | Continuous Drain Current <sup>1</sup>                             | 30         | A                  |
| $I_D @ T_A=70^\circ\text{C}$ | Continuous Drain Current <sup>1</sup>                             | 21         | A                  |
| IDM                          | Pulsed Drain Current <sup>2</sup>                                 | 36         | A                  |
| EAS                          | Single Pulse Avalanche Energy <sup>3</sup>                        | 31         | mJ                 |
| IAS                          | Avalanche Current   | 25         | A                  |
| $P_D @ T_A=25^\circ\text{C}$ | Total Power Dissipation <sup>4</sup>                              | 1.9        | W                  |
| TSTG                         | Storage Temperature Range   | -55 to 150 | $^\circ\text{C}$   |
| $T_J$                        | Operating Junction Temperature Range                              | -55 to 150 | $^\circ\text{C}$   |
| $R_{\theta JA}$              | Thermal Resistance Junction-ambient <sup>1</sup> ( $t \leq 10s$ ) | 25         | $^\circ\text{C/W}$ |
| $R_{\theta JC}$              | Thermal Resistance Junction-ambient <sup>1</sup>                  | 8          | $^\circ\text{C/W}$ |

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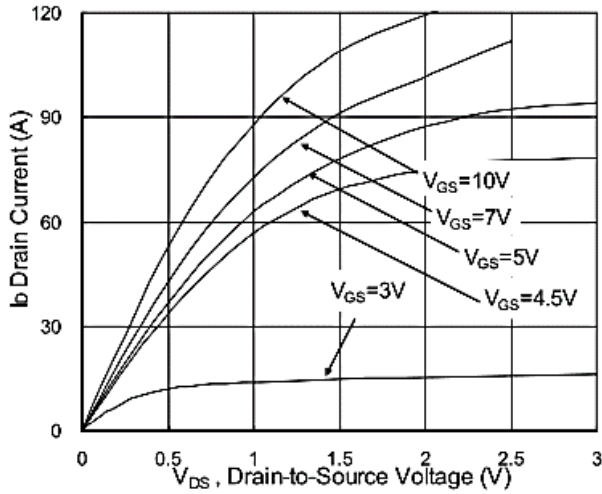
### Electrical Characteristics (T<sub>c</sub>=25°C unless otherwise noted)

| Symbol                 | Parameter                                      | Conditions   | Min. | Typ.  | Max. | Unit  |
|------------------------|--|--|------|-------|------|-------|
| BVDSS                  | Drain-Source Breakdown Voltage                 | V <sub>GS</sub> =0V, I <sub>D</sub> =250uA   | 40   | 44    | ---  | V     |
| ΔBVDSS/ΔT <sub>J</sub> | BVDSS Temperature Coefficient                  | Reference to 25°C, I <sub>D</sub> =1mA   | ---  | 0.034 | ---  | V/°C  |
| RDS(ON)                | Static Drain-Source On-Resistance <sup>2</sup> | V <sub>GS</sub> =10V, I <sub>D</sub> =8A   | ---  | 11    | 14   | mΩ    |
|                        |  | V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A  | ---  | 13    | 18   |       |
| VGS(th)                | Gate Threshold Voltage                         | V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA                             | 1.0  | 1.6   | 2.5  | V     |
| ΔVGS(th)               | VGS(th) Temperature Coefficient                |  | ---  | -5.64 | ---  | mV/°C |
| IDSS                   | Drain-Source Leakage Current                   | V <sub>DS</sub> =32V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C                      | ---  | ---   | 1    | uA    |
|                        |  | V <sub>DS</sub> =32V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C                      | ---  | ---   | 5    |       |
| IGSS                   | Gate-Source Leakage Current                    | V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V   | ---  | ---   | ±100 | nA    |
| gfs                    | Forward Transconductance                       | V <sub>DS</sub> =5V, I <sub>D</sub> =8A  | ---  | 36    | ---  | S     |
| R <sub>g</sub>         | Gate Resistance                                | V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz                                     | ---  | 2.1   | ---  | Ω     |
| Q <sub>g</sub>         | Total Gate Charge (4.5V)                       | V <sub>DS</sub> =20V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A                      | ---  | 10.7  | ---  | nC    |
| Q <sub>gs</sub>        | Gate-Source Charge                             |  | ---  | 3.3   | ---  | nC    |
| Q <sub>gd</sub>        | Gate-Drain Charge                              |  | ---  | 4.2   | ---  | nC    |
| T <sub>d(on)</sub>     | Turn-On Delay Time                             | V <sub>DD</sub> =12V V <sub>GS</sub> =10V R <sub>G</sub> =3.3Ω<br>I <sub>D</sub> =6A | ---  | 8.6   | ---  | ns    |
| T <sub>r</sub>         | Rise Time                                      |  | ---  | 3.4   | ---  | ns    |
| T <sub>d(off)</sub>    | Turn-Off Delay Time                            |  | ---  | 24.8  | ---  | ns    |
| T <sub>f</sub>         | Fall Time                                      |  | ---  | 2.2   | ---  | ns    |
| C <sub>iss</sub>       | Input Capacitance                              | V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz                                    | ---  | 1314  | ---  | pF    |
| C <sub>oss</sub>       | Output Capacitance                             |  | ---  | 120   | ---  |       |
| C <sub>rss</sub>       | Reverse Transfer Capacitance                   |  | ---  | 88    | ---  |       |
| I <sub>S</sub>         | Continuous Source Current <sup>1,5</sup>       | V <sub>G</sub> =V <sub>D</sub> =0V, Force Current                                    | ---  | ---   | 8.5  | A     |
| I <sub>SM</sub>        | Pulsed Source Current <sup>2,5</sup>           |  | ---  | ---   | 34   | A     |
| VSD                    | Diode Forward Voltage <sup>2</sup>             | V <sub>GS</sub> =0V, I <sub>S</sub> =1A, T <sub>J</sub> =25°C                        | ---  | ---   | 1.2  | V     |

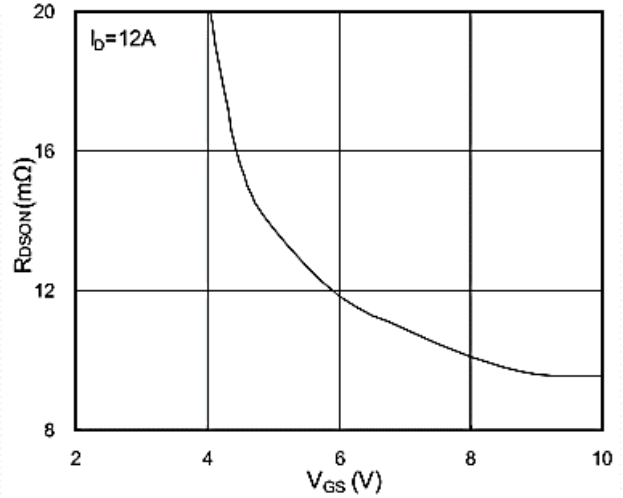
#### Note :

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=32V, V<sub>GS</sub>=10V, L=0.1Mh, I<sub>AS</sub>=22A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

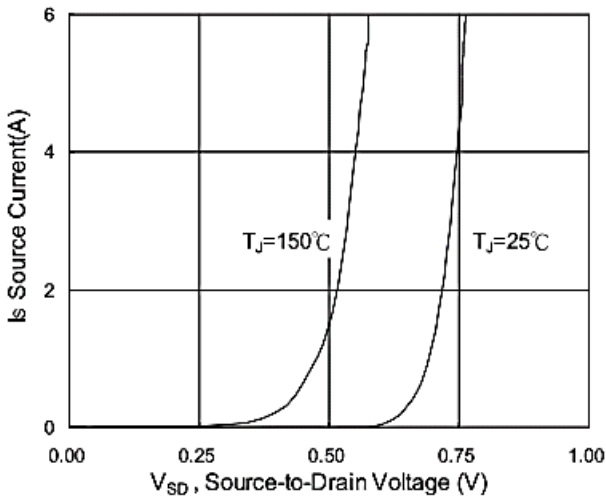
**Typical Characteristics**



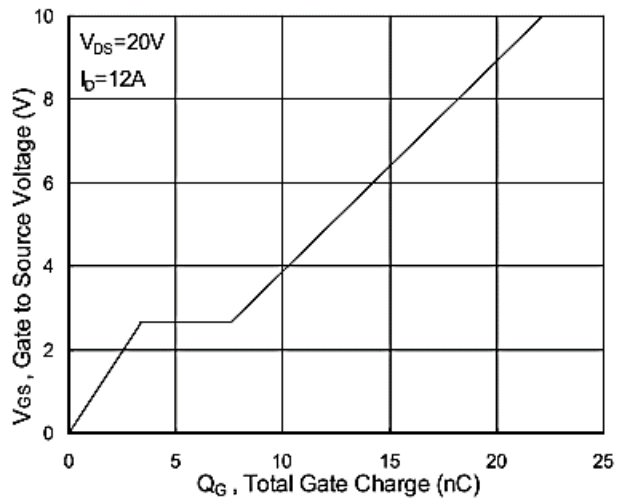
**Fig.1 Typical Output Characteristics**



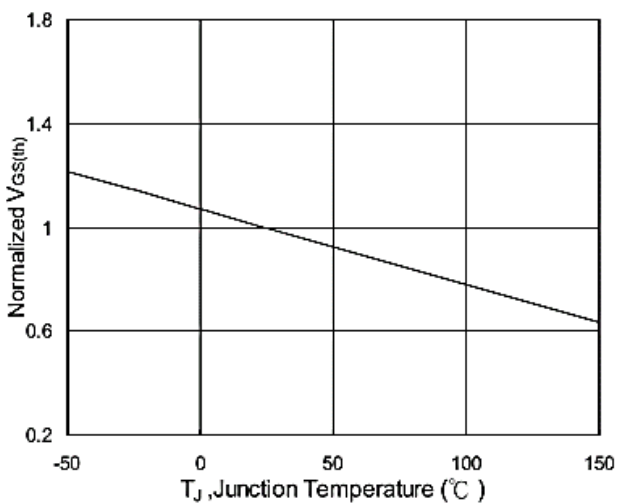
**Fig.2 On-Resistance vs. G-S Voltage**



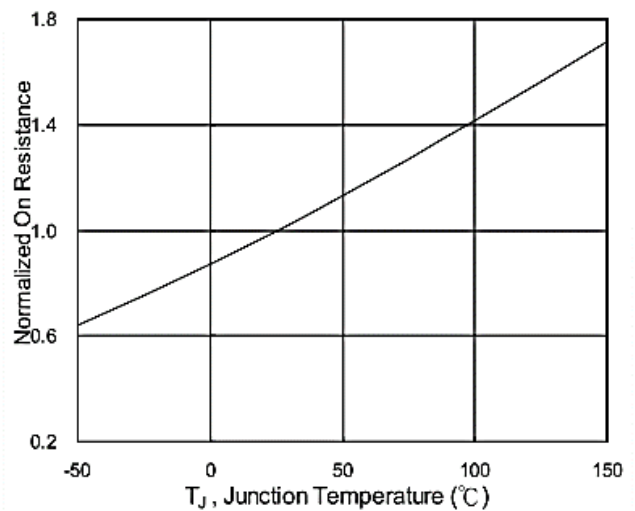
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

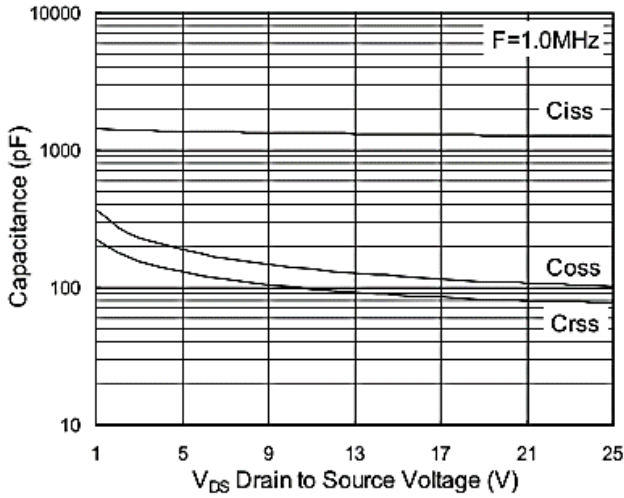


**Fig.5 V<sub>GS(th)</sub> vs. T<sub>J</sub>**

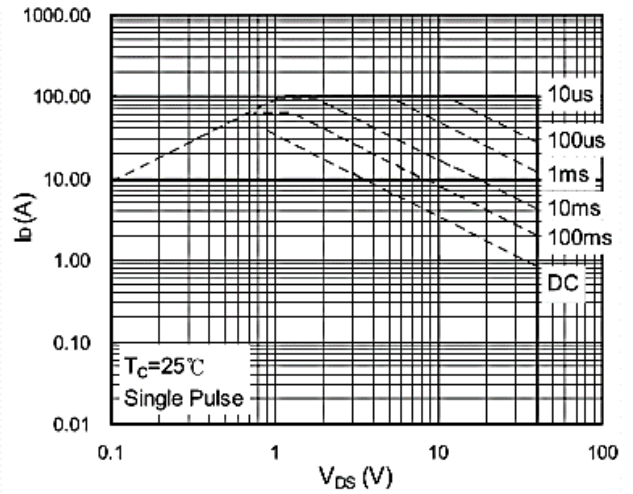


**Fig.6 Normalized R<sub>DS(on)</sub> vs. T<sub>J</sub>**

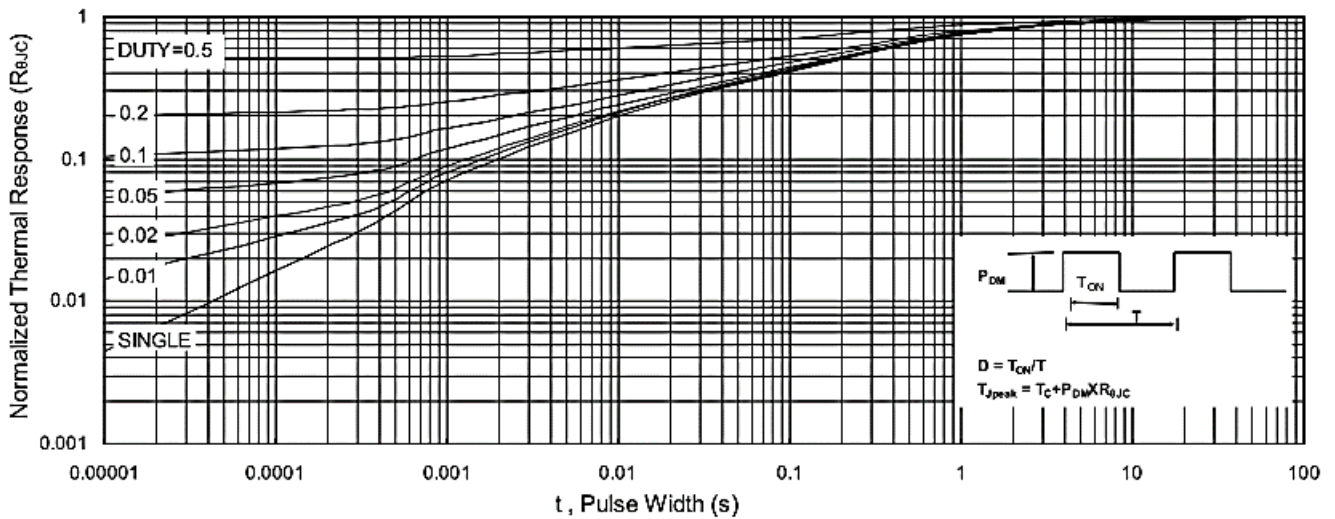




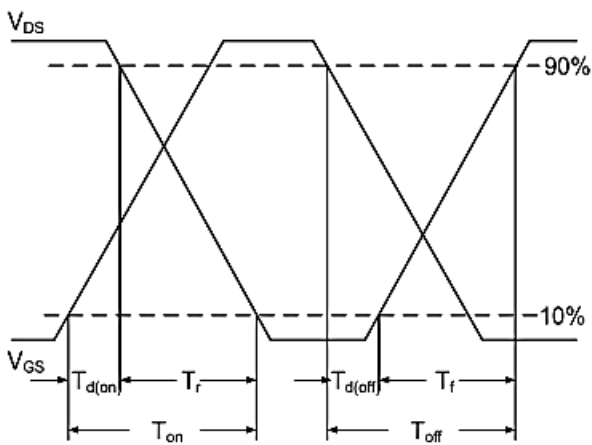
**Fig.7 Capacitance**



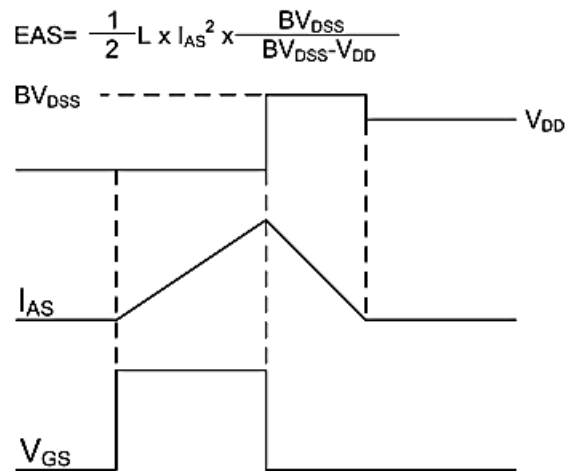
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

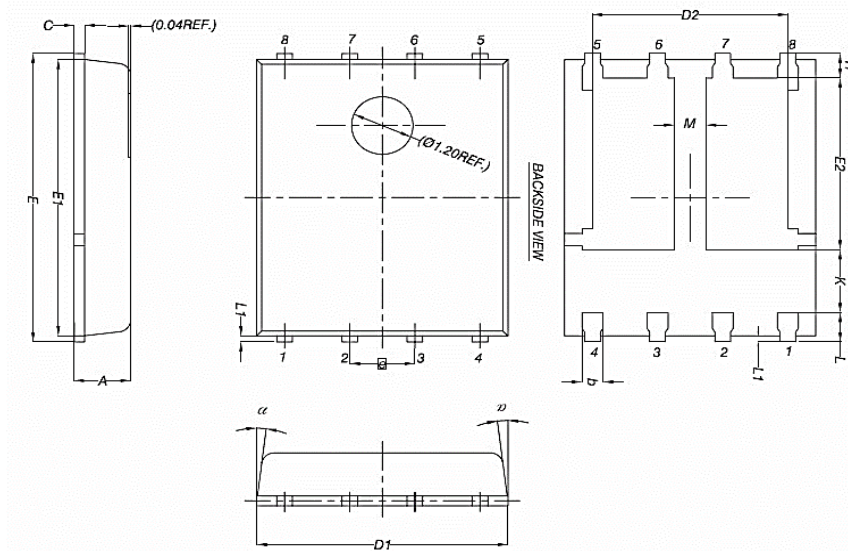


**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**

### Package Mechanical Data-DFN5\*6-8L-JQ Double



| Symbol | Common  |      |      |
|--------|---------|------|------|
|        | mm      |      |      |
|        | Mim     | Nom  | Max  |
| A      | 0.90    | 1.00 | 1.10 |
| b      | 0.33    | 0.41 | 0.51 |
| C      | 0.20    | 0.25 | 0.30 |
| D1     | 4.80    | 4.90 | 5.00 |
| D2     | 3.61    | 3.81 | 3.96 |
| E      | 5.90    | 6.00 | 6.10 |
| E1     | 5.70    | 3.30 | 3.45 |
| E2     | 3.38    | 3.05 | 3.20 |
| e      | 1.27BSC |      |      |
| H      | 0.41    | 0.51 | 0.61 |
| K      | 1.10    | --   | --   |
| L      | 0.51    | 0.61 | 0.71 |
| L1     | 0.06    | 0.13 | 0.20 |
| M      | 0.50    | --   | --   |
| a      | 0°      | --   | 12°  |

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